Supporting Information

Low-Temperature Thermally-Annealed Niobium Oxide Thin Films as a Minimally Color Changing Ion Storage Layer in Solution-Processed Polymer Electrochromic Devices

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Table of Contents **Page number**

X-ray diffraction patterns of UVO-150 °C and 300 °C annealed a-Nb_2O_5 thin films S-3

FTIR spectrum of a bare glass substrate S-3

AFM images of the a-Nb_2O_5 thin films (a) before and (b) after UVO treatment S-3

Cyclic voltammogram of the ECP-black in 0.2 M LiTFSI PC S-4

The change of optical density versus the charge density of the a-Nb_2O_5/ECP-black ECD S-4

Cyclic voltammogram of the a-Nb_2O_5/ECP-magenta two-electrode cell
in 0.2 M LiTFSI PC S-5

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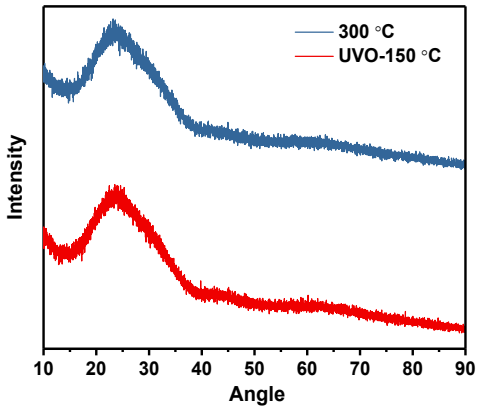

Figure S1. X-ray diffraction patterns of UVO-150 °C and 300 °C annealed a-Nb_2O_5 thin films.

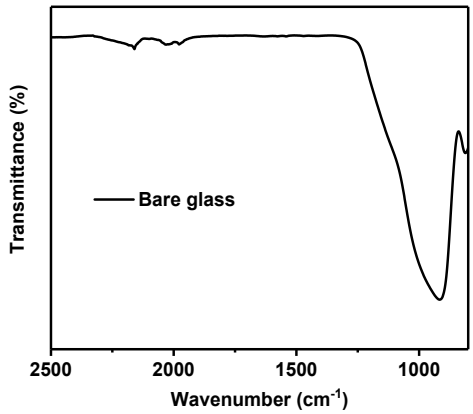

Figure S2. FTIR spectrum of a bare glass substrate.

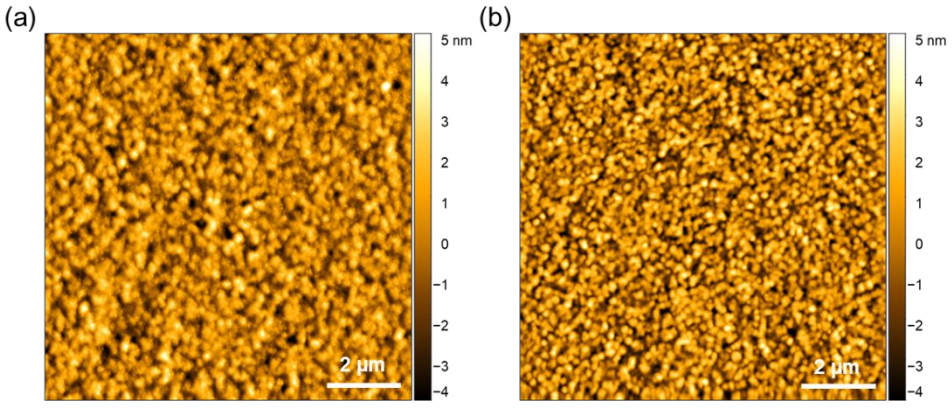

Figure S3. AFM images of the a-Nb_2O_5 thin films (a) before and (b) after UVO treatment.

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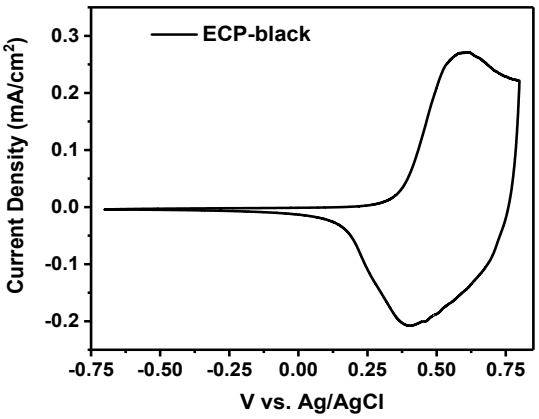

Figure S4. Cyclic voltammogram of the ECP-black in 0.2 M LiTFSI PC.

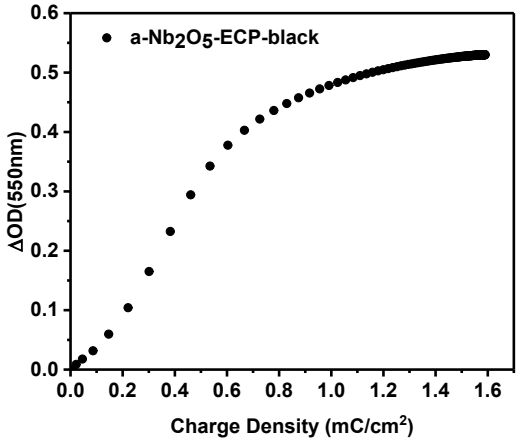

Figure S5. The change of optical density versus the charge density of the a-Nb_2O_5/ECP-black ECD.

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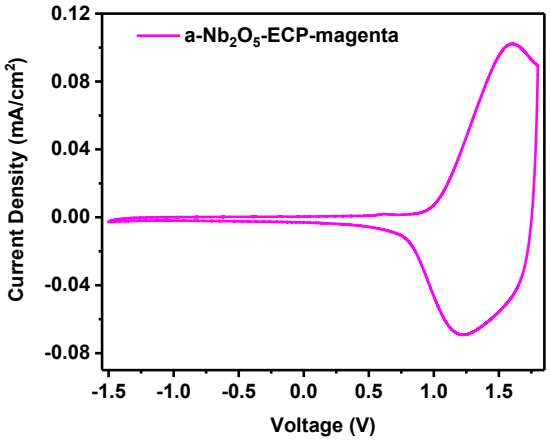

Figure S6. Cyclic voltammogram of the a-Nb_2O_5/ECP-magenta two-electrode cell in 0.2 M LiTFSI PC.

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